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TRIPLE DIGIT LED DISPLAY (0.4 Inch)



Lead-Free Parts

LTD415/66F-XX-PF

**DATA SHEET**

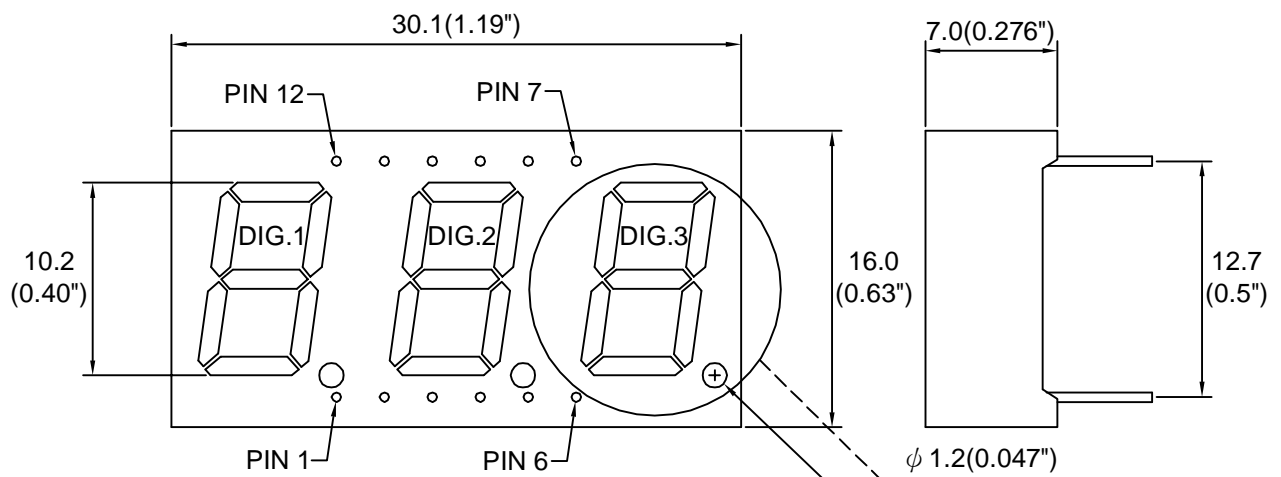
DOC. NO : QW0905-LTD415/66F-XX-PF

REV. : A

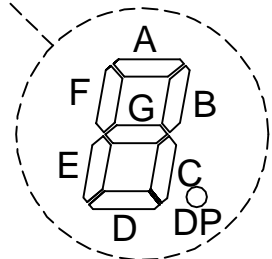
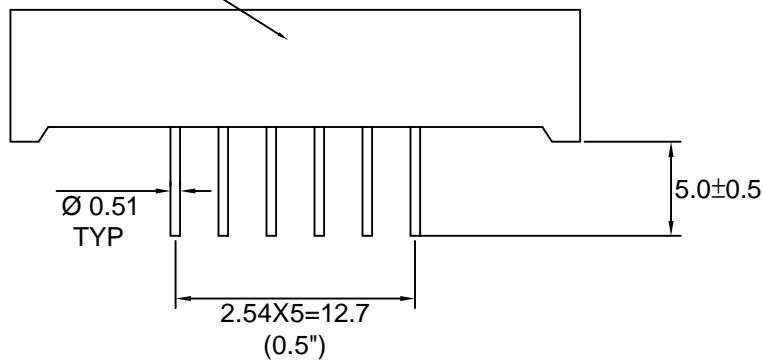
DATE : 02 - Jun. - 2011



Package Dimensions



LTD415/66F-XX-PF  
LIGITEK

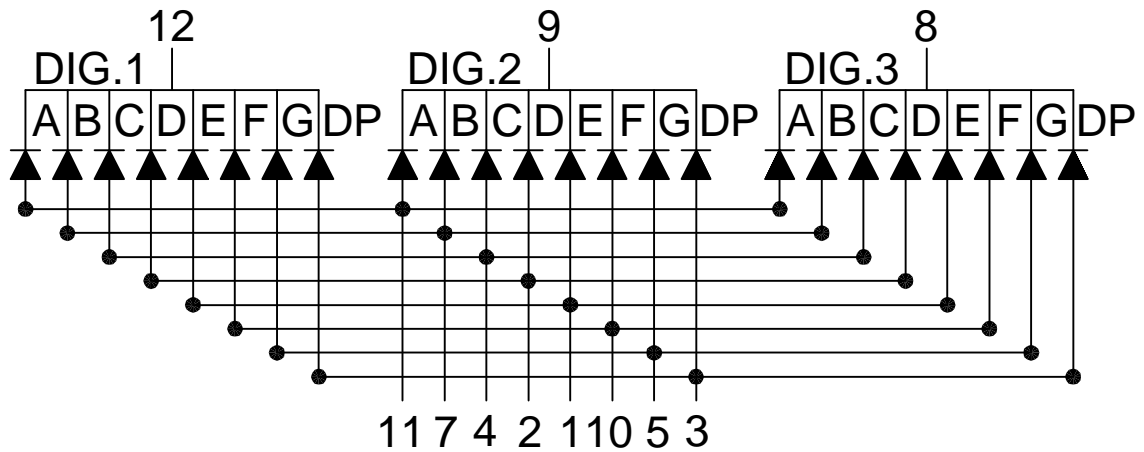


PIN NO.1 →

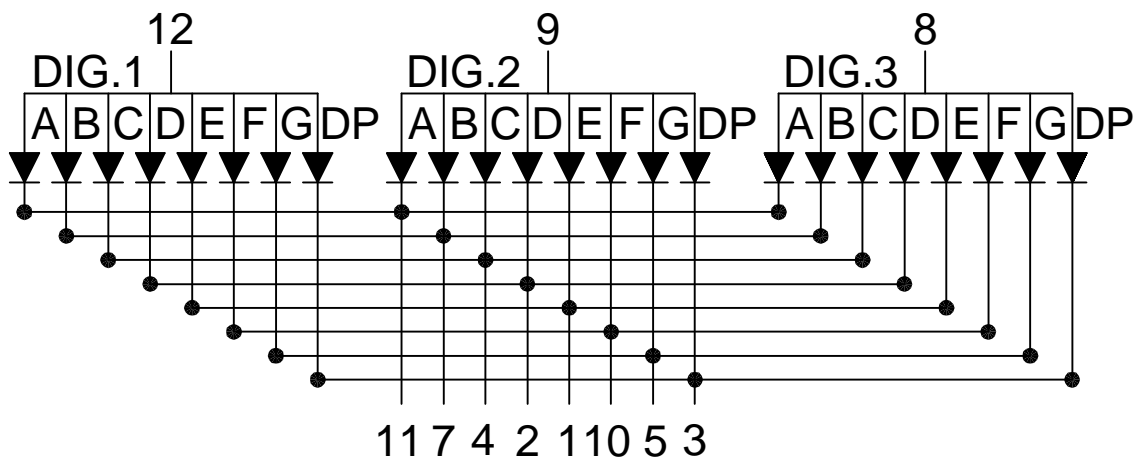
Note : 1.All dimension are in millimeters and (Inch) tolerance is  $\pm 0.25\text{mm}$  unless otherwise noted.  
2.Specifications are subject to change without notice.

Internal Circuit Diagram

LTD4156F-XX-PF



LTD4166F-XX-PF



### Electrical Connection

PIN NO.1	LTD4156F-XX-PF	PIN NO.1	LTD4166F-XX-PF
1	Anode E	1	Cathode E
2	Anode D	2	Cathode D
3	Anode DP	3	Cathode DP
4	Anode C	4	Cathode C
5	Anode G	5	Cathode G
6	No Connect	6	No Connect
7	Anode B	7	Cathode B
8	Common Cathode Dig.3	8	Common Anode Dig.3
9	Common Cathode Dig.2	9	Common Anode Dig.2
10	Anode F	10	Cathode F
11	Anode A	11	Cathode A
12	Common Cathode Dig.1	12	Common Anode Dig.1

### Absolute Maximum Ratings at Ta=25 °C

Parameter	Symbol	Ratings	UNIT
		HRF	
Forward Current Per Chip	IF	30	mA
Peak Forward Current Per Chip (Duty 1/10,0.1ms Pulse Width)	IFP	90	mA
Power Dissipation Per Chip	PD	75	mW
Reverse Current Per Any Chip	Ir	10	$\mu A$
Electrostatic Discharge ( * )	ESD	2000	V
Operating Temperature	Topr	-25 ~ +85	°C
Storage Temperature	Tstg	-25 ~ +85	°C

\* Static Electricity or power surge will damage the LED. Use of a conductive wrist band or anti-electrosatic glove is recommended when handing these LED. All devices, equipment and machinery must be properly grounded.

### Part Selection And Application Information(Ratings at 25°C)

PART NO	CHIP		common cathode or anode	$\lambda D$ (nm)	$\Delta \lambda$ (nm)	Electrical					IV-M
	Material	Emitted				Vf(v)			Iv(mcd)		
						Min.	Typ.	Max.	Min.	Typ.	
LTD4156F-XX-PF	AlGaInP	Red	Common Cathode	630	20	1.5	1.7	2.4	21.5	31.0	2:1
LTD4166F-XX-PF			Common Anode								

Note : 1.The forward voltage data did not including  $\pm 0.1V$  testing tolerance.  
2. The luminous intensity data did not including  $\pm 15\%$  testing tolerance.

**Test Condition For Each Parameter**

Parameter	Symbol	Unit	Test Condition
Forward Voltage Per Chip	V <sub>f</sub>	volt	I <sub>f</sub> =20mA
Luminous Intensity Per Chip	I <sub>v</sub>	mcd	I <sub>f</sub> =10mA
Dominant Wavelength	$\lambda D$	nm	I <sub>f</sub> =20mA
Spectral Line Half-Width	$\Delta \lambda$	nm	I <sub>f</sub> =20mA
Reverse Current Any Chip	I <sub>r</sub>	$\mu A$	V <sub>r</sub> =5V
Luminous Intensity Matching Ratio	IV-M		

## Typical Electro-Optical Characteristics Curve

### HRF CHIP

Fig.1 Forward current vs. Forward Voltage

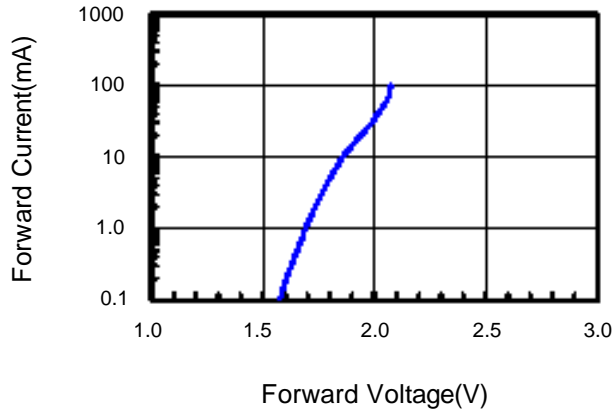


Fig.2 Relative Intensity vs. Forward Current

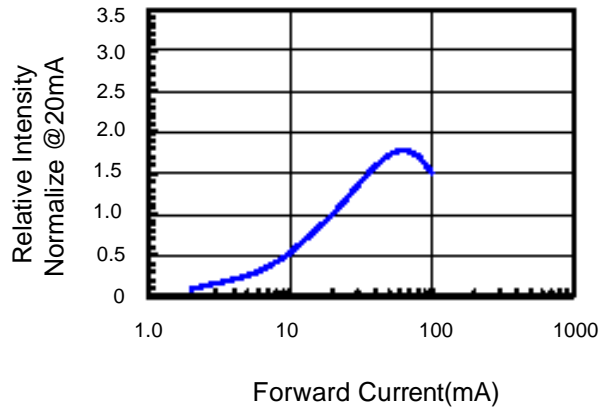


Fig.3 Forward Voltage vs. Temperature

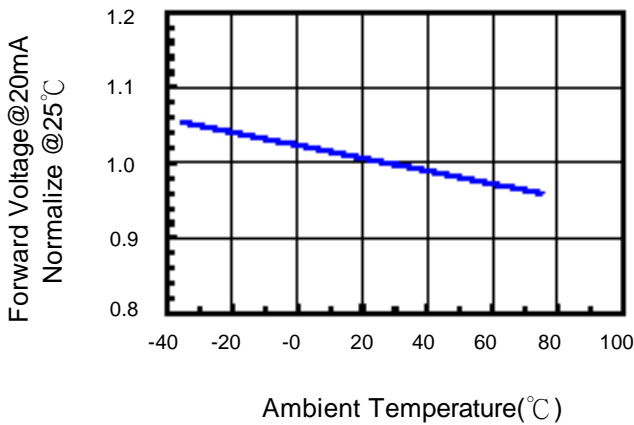


Fig.4 Relative Intensity vs. Temperature

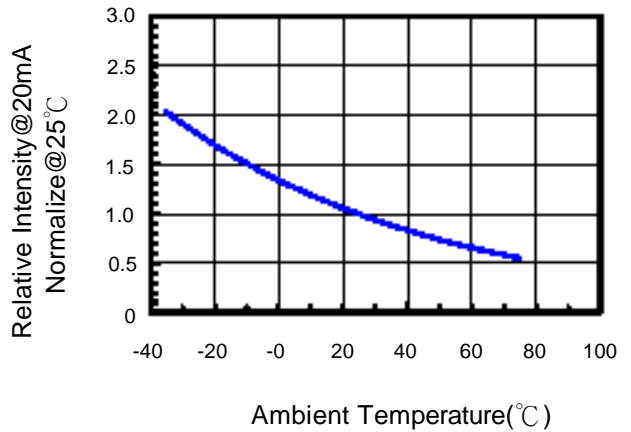
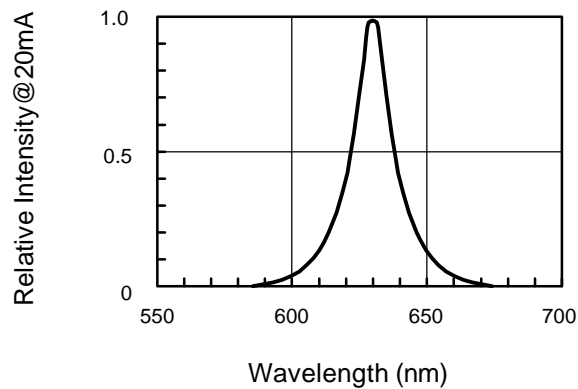


Fig.5 Relative Intensity vs. Wavelength

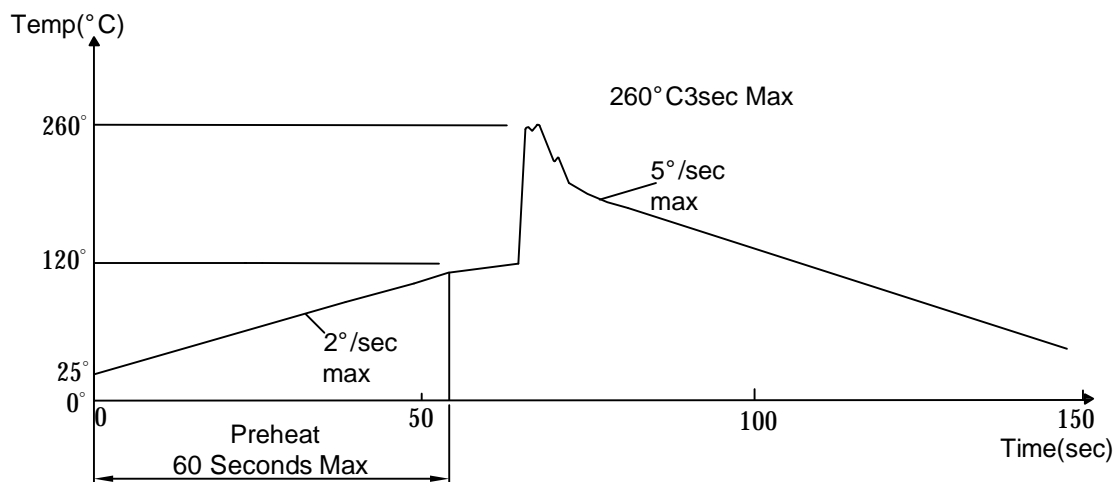


**Soldering Condition(Pb-Free)****1.Iron:**

Soldering Iron:30W Max  
Temperature 350 ° C Max  
Soldering Time:3 Seconds Max(One time only)  
Distance:Solder Temperature 1/16 Inch Below Seating  
Plane For 3 Seconds At 260 ° C

**2.Wave Soldering Profile**

Dip Soldering  
Preheat: 120° C Max  
Preheat time: 60seconds Max  
Ramp-up  
2° C/sec(max)  
Ramp-Down:-5° C/sec(max)  
Solder Bath:260° C Max  
Dipping Time:3 seconds Max  
Distance:Solder Temperature 1/16 Inch Below Seating  
Plane For 3 Seconds At 260° C



Note: 1.Wave solder should not be made more than one time.  
2.You can just only select one of the soldering conditions as above.



**Reliability Test:**

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=10mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and thermal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 °C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 °C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 °C±5°C 2.RH=90%~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 °C±5°C & -40 °C±5°C (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 °C±5°C 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 °C±5°C 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2